

AN3313, AN3313S

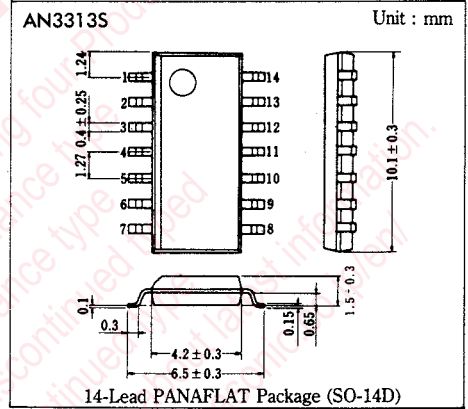
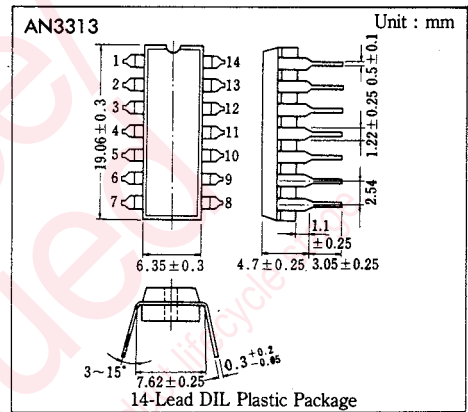
Head Amplifier Circuits for VTR (2-Head Type)

Outline

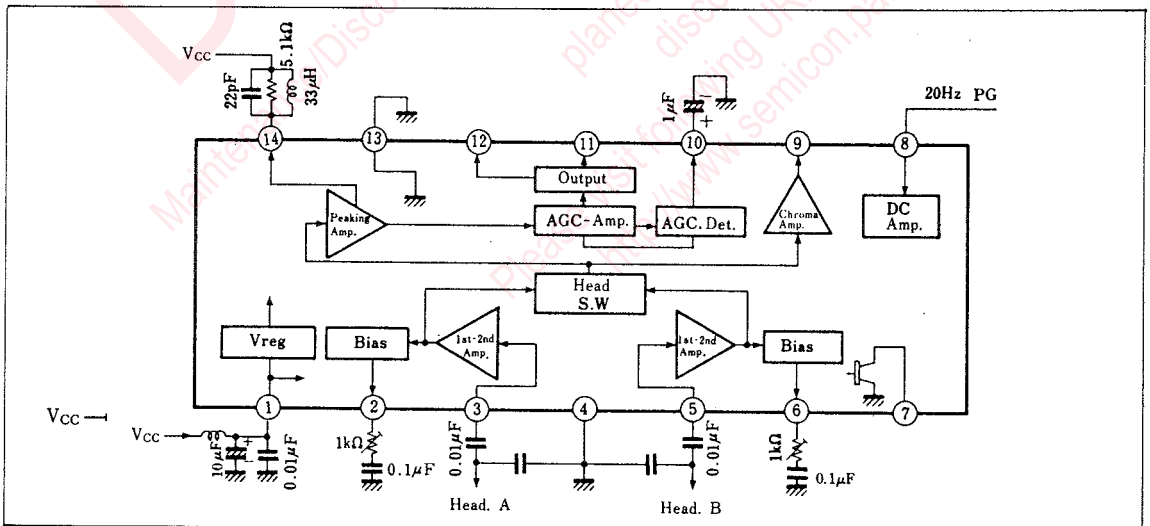
The AN3313 and the AN3313S are integrated circuits designed for head amplifier circuits for VTR (2-head type).

Features

- Supply voltage : $V_{CC}=5V$
- Built-in peaking amplifier circuit
- Less noise voltage to input ($1 \mu V_{rms}$)



Block Diagram



■ Pin

Pin No.	Pin Name	Pin No.	Pin Name
1	V _{CC}	8	PG Pulse Input
2	CH1 Damping Adjustment	9	Chroma Signal Output
3	CH1 Input	10	AGC Level Detection
4	GND	11	AGC Output B
5	CH2 Input	12	AGC Output A
6	CH2 Damping Adjustment	13	GND
7	ON Switch at PB	14	Peaking

■ Absolute Maximum Ratings (T_a=25°C)

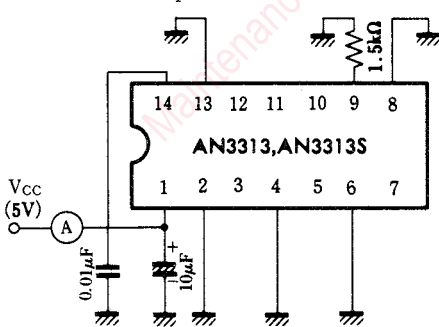
Item	Symbol	Rating	Unit
Supply Voltage	V _{CC}	6.0	V
Power Dissipation (T _a =70°C)	P _D	130	mW
Operating Ambient Temperature	T _{opr}	-20~+70	°C
Storage Temperature	T _{stg}	-55~+150	°C

■ Electrical Characteristics (V_{CC}=5V, T_a=25°C)

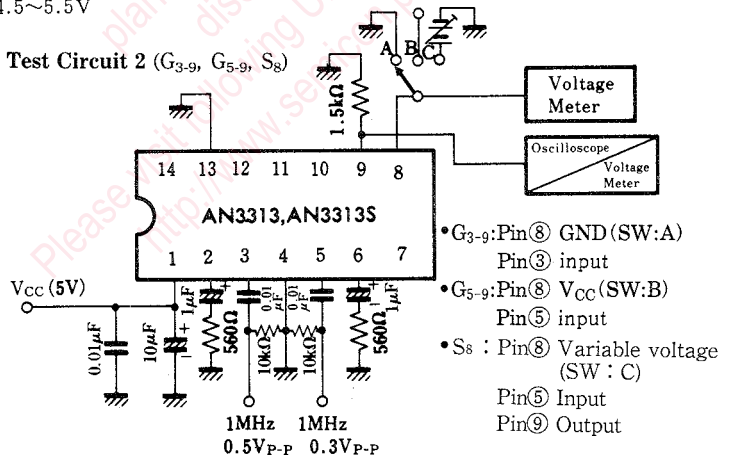
Item	Symbol	Test Circuit	Condition	min.	typ.	max.	Unit
Circuit Current	I ₁	1	②, ⑥, ⑧ GND. ⑨ 1.5×Ω GND. ⑭ V _{CC}	10		24	mA
Ch1 Gain	G ₃₋₉	2	③ 1MHz, 0.5mV _{P-P} . ⑨ Out	52.5		62.5	dB
Ch2 Gain	G ₅₋₉	2	⑤ 1MHz, 0.5mV _{P-P} . ⑨ Out	52.5		62.5	dB
AGC Output Amplitude	v ₁₂	3	③ 4MHz, 0.3mV _{P-P} . ⑫ Out	154		286	mV _{P-P}
AGC Control Sensitivity	Δv ₁₂	3	③ 4MHz, 0.3mV _{P-P} . ⑫ Out			3	dB
PG Switch Changeover Sensitivity	S ₈	2	③ 1MHz, 0.5mV _{P-P} . ⑥ GND ⑧ Variable voltage ⑨ out			3.5	V
Noise Voltage Referred to Input(1)	V _{ni1}	4	⑥ GND ⑨ Out 1MHz BPF added			1	μV _{rms}
Noise Voltage Referred to Input(2)	V _{ni2}	4	⑧ V _{CC} ⑨ Out 1MHz BPF added			1	μV _{rms}

Note : Operating supply voltage range V_{CC(oper)}=4.5~5.5V

Test Circuit 1 (I₁)



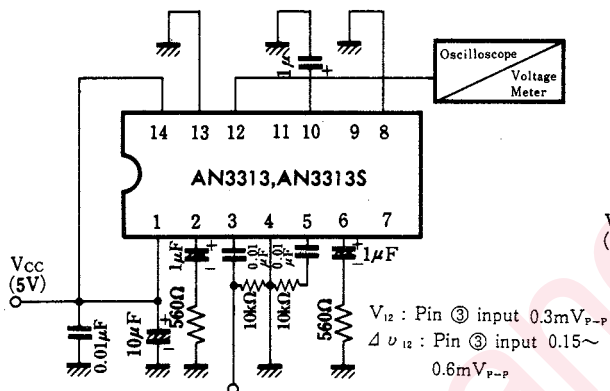
Test Circuit 2 (G₃₋₉, G₅₋₉, S₈)



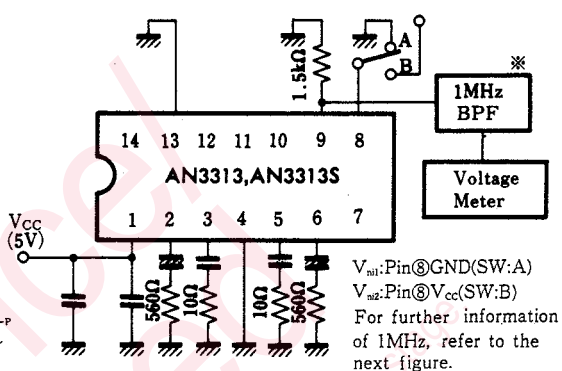
- G₃₋₉: Pin ⑧ GND (SW:A)
Pin ③ input
- G₅₋₉: Pin ⑧ V_{CC} (SW:B)
Pin ⑤ input
- S₈ : Pin ⑧ Variable voltage (SW:C)
Pin ⑤ Input
Pin ⑨ Output

Increasing the electric potential of Pin ⑧ from 0V, measure the electric potential of Pin ⑧ when Pin ⑨ output appears.

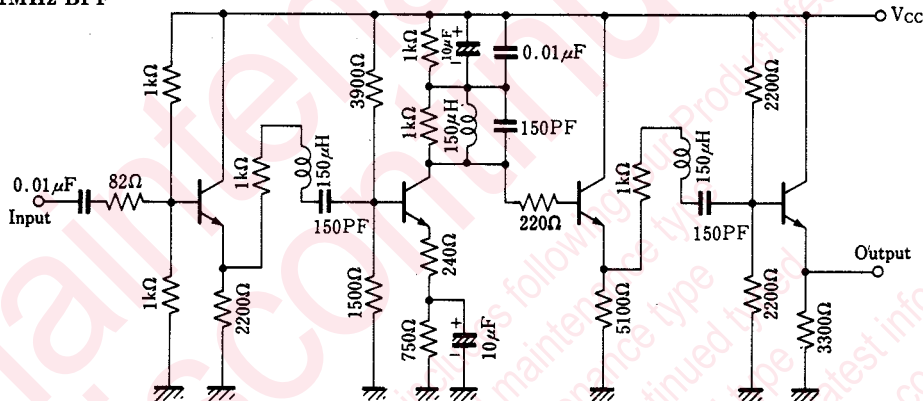
Test Circuit 3 (v_{i2} , Δv_{i2})



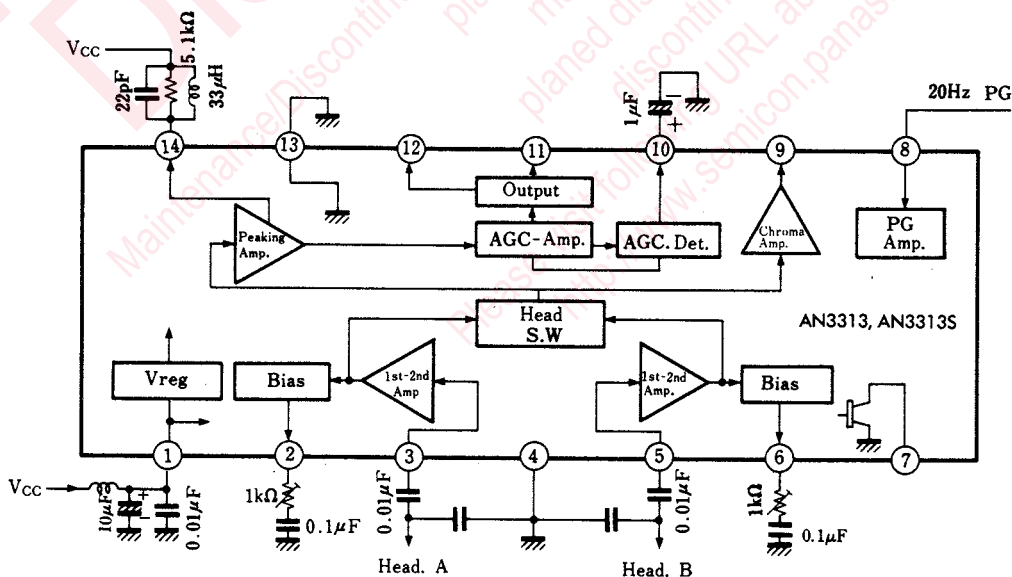
Test Circuit 4 (V_{ni1} , V_{ni2})



* 1MHz BPF



■ Application Circuit



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